

G01B

- 3/1084 . . Tapes combined with arrangements for functions other than measuring lengths
- 2003/1087 . . . {for illuminating}
- 3/1089 . . . for marking, drawing or cutting
- 3/1092 . . . for performing length measurements and at least one other measurement of a different nature, e.g. bubble-type level
- 3/1094 . . . for recording information or for performing calculations
- 2003/1097 . . . {Tape measures with an adhesive surface}
- 3/11 . Chains for measuring length
- 3/12 . Measuring wheels
- 3/14 . Templates for checking contours {(templates for mounting doors or windows [E04F 21/0007](#))}
- 3/16 . Compasses, i.e. with a pair of pivoted arms
- 3/163 . . {without measuring scale}
- 3/166 . . {provided with a measuring scale}
- 3/18 . Micrometers
- 3/20 . Slide gauges
- 3/205 . . {provided with a counter for digital indication of the measured dimension}
- 3/22 . Feeler-pin gauges, e.g. dial gauges (for measuring contours or curvatures [G01B 5/20](#))
- 3/24 . . with open yoke, i.e. calipers
- 3/26 . . Plug gauges
- 3/28 . . Depth gauges
- 3/30 . Bars, blocks, or strips in which the distance between a pair of faces is fixed, although it may be preadjustable, e.g. end measure, feeler strip
- 3/303 . . {pre-adjustable, e.g. by means of micrometerscrew}
- 3/306 . . . {with inclined slide plane}
- 3/32 . . Holders therefor
- 3/34 . Ring or other apertured gauges, e.g. "go/no-go" gauge
- 3/36 . . for external screw-threads
- 3/38 . Gauges with an open yoke and opposed faces, i.e. calipers, in which the internal distance between the faces is fixed, although it may be preadjustable
- 3/40 . . for external screw-threads
- 3/42 . . of limit-gauge type, i.e. "go/no-go" ([G01B 3/40 takes precedence](#))
- 3/44 . . . preadjustable for wear or tolerance
- 3/46 . Plug gauges for internal dimensions with engaging surfaces which are at a fixed distance, although they may be preadjustable
- 3/48 . . for internal screw-threads
- 3/50 . . of limit-gauge type, i.e. "go/no-go" ([G01B 3/48 takes precedence](#))
- 3/52 . . . preadjustable for wear or tolerance
- 3/56 . Gauges for measuring angles or tapers, e.g. conical calipers
- 3/563 . . {Protractors (for use in geodesy [G01C 1/00](#); protractor heads for drawing machines [B43L 13/08](#))}
- 3/566 . . {Squares}

5/00 Measuring arrangements characterised by the use of mechanical techniques

NOTE

When classifying in this group, specific mechanical measuring instruments can be further classified in group [G01B 3/00](#).

- 5/0002 . {Arrangements for supporting, fixing or guiding the measuring instrument or the object to be measured}
- 5/0004 . . {Supports ([G01B 5/025 takes precedence](#))}
- 5/0007 . . {Surface plates}
- 5/0009 . . {Guiding surfaces; Arrangements compensating for non-linearity there-of}
- 5/0011 . {Arrangements for eliminating or compensation of measuring errors due to temperature or weight}
- 5/0014 . . {due to temperature ([on machine tools B23Q 11/0003](#))}
- 5/0016 . . {due to weight ([on machine tools B23Q 11/001](#))}
- 5/0018 . {for measuring key-ways}
- 5/0021 . {for measuring the volumetric dimension of an object}
- 5/0023 . {Measuring of sport goods, e.g. bowling accessories, golfclubs, game balls}
- 5/0025 . {Measuring of vehicle parts ([G01B 5/003 takes precedence](#))}
- 5/0028 . . {Brakes, brakeshoes, clutches}
- 5/003 . {Measuring of motor parts}
- 5/0032 . . {Valves, actuating devices for valves}
- 5/0035 . {Measuring of dimensions of trees}
- 5/0037 . {Measuring of dimensions of welds}
- 5/004 . for measuring coordinates of points
- 5/008 . . using coordinate measuring machines
- 5/012 . . . Contact-making feeler heads therefor
- 5/016 Constructional details of contacts
- 5/02 . for measuring length, width or thickness ([G01B 5/004](#), [G01B 5/08 take precedence](#))
- 5/025 . . {Measuring of circumference; Measuring length of ring-shaped articles ([G01B 5/0035 takes precedence](#))}
- 5/04 . . specially adapted for measuring length or width of objects while moving
- 5/043 . . . {for measuring length}
- 5/046 . . . {for measuring width}
- 5/06 . . for measuring thickness
- 5/061 . . . {height gauges}
- 5/063 {provided with a slide which may be moved along a vertical support by means of a micrometer screw}
- 5/065 {provided with a slide which may be fixed along its vertical support in discrete calibrated position}
- 5/066 . . . {of coating}
- 5/068 . . . {of objects while moving ([G01B 5/066 takes precedence](#))}
- 5/08 . for measuring diameters {([G01B 5/0035 takes precedence](#); measuring radius of curvature [G01B 5/213](#))}
- 5/10 . . of objects while moving
- 5/12 . . internal diameters
- 5/14 . for measuring distance or clearance between spaced objects or spaced apertures ([G01B 5/24 takes precedence](#))
- 5/143 . . {between holes on a workpiece}

- 5/146 . . {measuring play on bearings}
- 5/16 . . between a succession of regularly spaced objects or regularly spaced apertures
- 5/163 . . . {of screw-threads}
- 5/166 . . . {of gear teeth}
- 5/18 . for measuring depth
- 5/20 . for measuring contours or curvatures
- 5/201 . . {for measuring roundness}
- 5/202 . . {of gears}
- 5/204 . . {of screw-threads}
- 5/205 . . {of turbine blades or propellers}
- 5/207 . . using a plurality of fixed, simultaneously operating transducers ([G01B 5/213](#) - [G01B 5/22](#) take precedence)
- 5/213 . . for measuring radius of curvature
- 5/22 . . Spherometers
- 5/24 . for measuring angles or tapers; for testing the alignment of axes
- 5/241 . . {for measuring conicity}
- 5/242 . . {Sine bars; Sine plates}
- 5/243 . . {for measuring chamfer ([see G01B 3/56](#))}
- 5/245 . . for testing perpendicularity
- 5/25 . . for testing the alignment of axes
- 5/252 . . . for measuring eccentricity, i.e. lateral shift between two parallel axes
- 5/255 . . for testing wheel alignment
- 5/26 . for measuring areas, e.g. planimeters
- 5/28 . for measuring roughness or irregularity of surfaces
- 5/285 . . {for controlling evenness}
- 5/30 . for measuring the deformation in a solid, e.g. mechanical strain gauge
- 7/00 Measuring arrangements characterised by the use of electric or magnetic techniques**
- 7/001 . {Constructional details of gauge heads ([G01B 7/012](#) takes precedence)}
- 7/002 . {Constructional details of contacts for gauges actuating one or more contacts ([G01B 7/016](#) takes precedence)}
- 7/003 . {for measuring position, not involving coordinate determination ([coordinate measuring G01B 7/004](#))}
- 7/004 . for measuring coordinates of points
- 7/008 . . using coordinate measuring machines
- 7/012 . . . Contact-making feeler heads therefor
- 7/016 Constructional details of contacts
- 7/02 . for measuring length, width or thickness ([G01B 7/004](#), [G01B 7/12](#) take precedence)
- 7/023 . . {for measuring distance between sensor and object ([G01B 7/082](#) and [G01B 7/102](#) take precedence)}
- 7/026 . . {for measuring length of cable, band or the like, which has been paid out, e.g. from a reel ([measuring length of objects while moving G01B 7/04](#))}
- 7/04 . . specially adapted for measuring length or width of objects while moving
- 7/042 . . . {for measuring length}
- 7/044 {using capacitive means}
- 7/046 {using magnetic means}
- 7/048 . . . {for measuring width}
- 7/06 . . for measuring thickness {([measuring during the manufacture of coatings C23C 14/54](#))}
- 7/063 . . . {using piezoelectric resonators}
- 7/066 {for measuring thickness of coating (apparatus or processes for the manufacture of piezoelectric or electrostrictive resonators for obtaining desired frequency [H03H 3/04](#))}
- 7/08 . . . {using capacitive means}
- 7/082 {Height gauges}
- 7/085 {for measuring thickness of coating}
- 7/087 {for measuring of objects while moving ([G01B 7/085](#) takes precedence)}
- 7/10 . . . {using magnetic means, e.g. by measuring change of reluctance}
- 7/102 {Height gauges}
- 7/105 {for measuring thickness of coating}
- 7/107 {for measuring objects while moving ([G01B 7/105](#) takes precedence)}
- 7/12 . for measuring diameters
- 7/125 . . {of objects while moving}
- 7/13 . . Internal diameters
- 7/14 . for measuring distance or clearance between spaced objects or spaced apertures ([G01B 7/30](#) takes precedence)
- 7/142 . . {between holes on a workpiece}
- 7/144 . . {Measuring play on bearings}
- 7/146 . . {Measuring on gear teeth}
- 7/148 . . {Measuring on screw threads}
- 7/15 . . being regularly spaced
- 7/16 . for measuring the deformation in a solid, e.g. by resistance strain gauge
- 7/18 . . {using change in resistance}
- 7/20 . . . {formed by printed-circuit technique}
- 7/22 . . {using change in capacitance}
- 7/24 . . using change in magnetic properties
- 7/26 . for measuring depth
- 7/28 . for measuring contours or curvatures
- 7/281 . . {for measuring contour or curvature along an axis, e.g. axial curvature of a pipeline or along a series of feeder rollers}
- 7/282 . . {for measuring roundness}
- 7/283 . . {of gears}
- 7/284 . . {of screw-threads}
- 7/285 . . {of propellers or turbine blades}
- 7/286 . . {Spherometers}
- 7/287 . . using a plurality of fixed, simultaneously operating transducers ([G01B 7/293](#) takes precedence)
- 7/293 . . for measuring radius of curvature
- 7/30 . for measuring angles or tapers; for testing the alignment of axes
- 7/305 . . for testing perpendicularity
- 7/31 . . for testing the alignment of axes
- 7/312 . . . for measuring eccentricity, i.e. lateral shift between two parallel axes
- 7/315 . . for testing wheel alignment
- 7/32 . for measuring areas
- 7/34 . for measuring roughness or irregularity of surfaces
- 7/345 . . {for measuring evenness}

9/00 Measuring instruments characterised by the use of optical techniques

NOTE

When classifying in this group, optical arrangements for measuring specific parameters can be further classified in group [G01B 11/00](#).

- 9/02 . Interferometers
- 9/02001 . . characterised by controlling or generating intrinsic radiation properties
- 9/02002 . . . using two or more frequencies
- 9/02003 using beat frequencies
- 9/02004 using frequency scans
- 9/02005 {using discrete frequency stepping or switching}
- 9/02007 . . . {Two or more frequencies or sources used for interferometric measurement (using only beat [G01B 9/02003](#))}
- 9/02008 {by using a frequency comb}
- 9/02009 {by using two or more low coherence lengths using different or varying spectral width}
- 9/0201 . . . {using temporal phase variation}
- 9/02011 . . . {using temporal polarization variation}
- 9/02012 . . . {using temporal intensity variation}
- 9/02014 {by using pulsed light}
- 9/02015 . . characterised by the beam path configuration
- 9/02016 . . . {contacting two or more objects}
- 9/02017 . . . with multiple interactions between the target object and light beams, e.g. beam reflections occurring from different locations
- 9/02018 Multipass interferometers, e.g. double-pass
- 9/02019 {contacting different points on same face of object}
- 9/02021 {contacting different faces of object, e.g. opposite faces}
- 9/02022 . . . {contacting one object by grazing incidence}
- 9/02023 . . . {Indirect probing of object, e.g. via influence on cavity or fibre}
- 9/02024 . . . {Measuring in transmission, i.e. light traverses the object}
- 9/02025 . . . {Interference between three or more discrete surfaces}
- 9/02027 . . . {Two or more interferometric channels or interferometers}
- 9/02028 {Two or more reference or object arms in one interferometer}
- 9/02029 . . . {Combination with non-interferometric systems, i.e. for measuring the object}
- 9/0203 {With imaging systems}
- 9/02031 {With non-optical systems, e.g. tactile}
- 9/02032 . . . {generating a spatial carrier frequency, e.g. by creating lateral or angular offset between reference and object beam (shearing interferometers [G01B 9/02098](#))}
- 9/02034 . . {characterised by particularly shaped beams or wavefronts}
- 9/02035 . . . {Shaping the focal point, e.g. elongated focus}
- 9/02036 {by using chromatic effects, e.g. a wavelength dependent focal point}
- 9/02037 {by generating a transverse line focus}
- 9/02038 . . . {Shaping the wavefront, e.g. generating a spherical wavefront}
- 9/02039 {by matching the wavefront with a particular object surface shape}
- 9/02041 . . {characterised by particular imaging or detection techniques}
- 9/02042 . . . {Confocal imaging}
- 9/02043 . . . {Imaging of the Fourier or pupil or back focal plane, i.e. angle resolved imaging}
- 9/02044 . . . {Imaging in the frequency domain, e.g. by using a spectrometer}
- 9/02045 . . . {using the Doppler effect}
- 9/02047 . . . {using digital holographic imaging, e.g. lensless phase imaging without hologram in the reference path}
- 9/02048 . . . {Rough and fine measurement}
- 9/02049 . . {characterised by particular mechanical design details}
- 9/0205 . . . {of probe head}
- 9/02051 . . . {Integrated design, e.g. on-chip or monolithic}
- 9/02052 . . . {Protecting, e.g. shock absorbing, arrangements}
- 9/02054 . . . {Hand held}
- 9/02055 . . Reduction or prevention of errors; Testing; Calibration
- 9/02056 . . . Passive reduction of errors
- 9/02057 {by using common path configuration, i.e. reference and object path almost entirely overlapping}
- 9/02058 {by particular optical compensation or alignment elements, e.g. dispersion compensation}
- 9/02059 {Reducing effect of parasitic reflections, e.g. cyclic errors}
- 9/02061 Reduction or prevention of effects of tilts or misalignment
- 9/02062 . . . {Active error reduction, i.e. varying with time}
- 9/02063 {by particular alignment of focus position, e.g. dynamic focussing in optical coherence tomography}
- 9/02064 {by particular adjustment of coherence gate, i.e. adjusting position of zero path difference in low coherence interferometry}
- 9/02065 {using a second interferometer before or after measuring interferometer}
- 9/02067 {by electronic control systems, i.e. using feedback acting on optics or light}
- 9/02068 {Auto-alignment of optical elements}
- 9/02069 {Synchronization of light source or manipulator and detector}
- 9/0207 . . . {Error reduction by correction of the measurement signal based on independently determined error sources, e.g. using a reference interferometer}
- 9/02071 {by measuring path difference independently from interferometer}
- 9/02072 {by calibration or testing of interferometer}
- 9/02074 {of the detector}
- 9/02075 . . . {of particular errors}
- 9/02076 {Caused by motion}
- 9/02077 {of the object}
- 9/02078 {Caused by ambiguity}
- 9/02079 {Quadrature detection, i.e. detecting relatively phase-shifted signals}
- 9/02081 {simultaneous quadrature detection, e.g. by spatial phase shifting}

- 9/02082 {Caused by speckles}
- 9/02083 . . {characterised by particular signal processing and presentation}
- 9/02084 . . . {Processing in the Fourier or frequency domain when not imaged in the frequency domain}
- 9/02085 . . . {Combining two or more images of different regions}
- 9/02087 . . . {Combining two or more images of the same region}
- 9/02088 . . . {Matching signals with a database}
- 9/02089 . . . {Displaying the signal, e.g. for user interaction}
- 9/0209 . . Low-coherence interferometers
- 9/02091 . . . Tomographic interferometers, e.g. based on optical coherence
- 9/02092 . . {Self-mixing interferometers, i.e. feedback of light from object into laser cavity}
- 9/02094 . . {Speckle interferometers, i.e. for detecting changes in speckle pattern}
- 9/02095 . . . {detecting deformation from original shape}
- 9/02096 . . . {detecting a contour or curvature}
- 9/02097 . . Self-interferometers
- 9/02098 . . . Shearing interferometers
- 9/021 . . using holographic techniques
- 9/023 . . . for contour producing
([G01B 9/025](#) - [G01B 9/029](#) take precedence)
- 9/025 . . . Double exposure technique
- 9/027 . . . in real time
- 9/029 . . . by time averaging
- 9/04 . Measuring microscopes
- 9/06 . Measuring telescopes
- 9/08 . Optical projection comparators
- 9/10 . Goniometers for measuring angles between surfaces
- 11/00 Measuring arrangements characterised by the use of optical techniques**
- NOTE**
- When classifying in this group, specific optical measuring instruments can be further classified in group [G01B 9/00](#).
- 11/002 . {for measuring two or more coordinates}
- 11/005 . . {coordinate measuring machines}
- 11/007 . . . {feeler heads therefor}
- 11/02 . for measuring length, width or thickness
([G01B 11/08](#) takes precedence)
- 11/022 . . {by means of tv-camera scanning}
- 11/024 . . {by means of diode-array scanning}
- 11/026 . . {by measuring distance between sensor and object ([G01B 11/0608](#) takes precedence)}
- 11/028 . . {by measuring lateral position of a boundary of the object ([G01B 11/022](#), [G01B 11/024](#), [G01B 11/04](#) take precedence)}
- 11/03 . . by measuring coordinates of points
- 11/04 . . specially adapted for measuring length or width of objects while moving
- 11/043 . . . {for measuring length}
- 11/046 . . . {for measuring width}
- 11/06 . . for measuring thickness {; e.g. of sheet material ([thickness measurement by thermal means G01B 21/085](#))}
- 11/0608 . . . {Height gauges}
- 11/0616 . . . {of coating}
- 11/0625 {with measurement of absorption or reflection}
- 11/0633 {using one or more discrete wavelengths}
- 11/0641 {with measurement of polarization}
- 11/065 {using one or more discrete wavelengths}
- 11/0658 {with measurement of emissivity or reradiation}
- 11/0666 {using an exciting beam and a detection beam including surface acoustic waves [SAW]}
- 11/0675 {using interferometry}
- 11/0683 {measurement during deposition or removal of the layer}
- 11/0691 . . . {of objects while moving ([G01B 11/0616](#) takes precedence)}
- 11/08 . for measuring diameters
- 11/10 . . of objects while moving
- 11/105 . . . {using photoelectric detection means}
- 11/12 . . internal diameters
- 11/14 . for measuring distance or clearance between spaced objects or spaced apertures ([G01B 11/26](#) takes precedence; [rangefinders G01C 3/00](#))
- 11/16 . for measuring the deformation in a solid, e.g. optical strain gauge
- 11/161 . . . {by interferometric means}
- 11/162 . . . {by speckle- or shearing interferometry}
- 11/164 . . . {by holographic interferometry}
- 11/165 . . . {by means of a grating deformed by the object}
- 11/167 . . . {by projecting a pattern on the object}
- 11/168 . . . {by means of polarisation}
- 11/18 . . {using photoelastic elements}
- 11/20 . . {using brittle lacquer}
- 11/22 . for measuring depth
- 11/24 . for measuring contours or curvatures
- 11/2408 . . {for measuring roundness}
- 11/2416 . . {of gears ([optical projection profile comparators G01B 9/08](#))}
- 11/2425 . . . {of screw-threads}
- 11/2433 . . . {for measuring outlines by shadow casting}
- 11/2441 . . . {using interferometry}
- 11/245 . . using a plurality of fixed, simultaneously operating transducers
([G01B 11/2408](#) - [G01B 11/2425](#), } [G01B 11/255](#) take precedence)
- 11/25 . . by projecting a pattern, e.g. {one or more lines,} moiré fringes on the object ([G01B 11/255](#) takes precedence {; image analysis for depth or shape recovery [G06T 7/50](#))}
- 11/2504 . . . {Calibration devices}
- 11/2509 . . . {Color coding}
- 11/2513 . . . {with several lines being projected in more than one direction, e.g. grids, patterns}
- 11/2518 . . . {Projection by scanning of the object}
- 11/2522 {the position of the object changing and being recorded}
- 11/2527 {with phase change by in-plane movement of the pattern}
- 11/2531 . . . {using several gratings, projected with variable angle of incidence on the object, and one detection device}
- 11/2536 . . . {using several gratings with variable grating pitch, projected on the object with the same angle of incidence}

11/254	. . . {Projection of a pattern, viewing through a pattern, e.g. moiré}	21/00	Measuring arrangements or details thereof, where the measuring technique is not covered by the other groups of this subclass, unspecified or not relevant
11/2545	. . . {with one projection direction and several detection directions, e.g. stereo}		
11/255	. . for measuring radius of curvature {(measuring diameter G01B 11/08)}		
11/26	. for measuring angles or tapers; for testing the alignment of axes		
11/27	. . for testing the alignment of axes {(means for centering or aligning a light guide within a ferrule G02B 6/3834)}		
11/272	. . . {using photoelectric detection means}	21/02	. for measuring length, width, or thickness (G01B 21/10 takes precedence)
11/275	. . for testing wheel alignment	21/04	. . by measuring coordinates of points
11/2755	. . . {using photoelectric detection means}	21/042	. . . {Calibration or calibration artifacts (G01B 3/30, G01B 9/02072 take precedence)}
11/28	. for measuring areas	21/045	. . . {Correction of measurements (G01B 9/02055 takes precedence)}
11/285	. . {using photoelectric detection means}	21/047	. . . {Accessories, e.g. for positioning, for tool-setting, for measuring probes}
11/30	. for measuring roughness or irregularity of surfaces	21/06	. . specially adapted for measuring length or width of objects while moving
11/303	. . {using photoelectric detection means}	21/065	. . . {for stretchable materials}
11/306	. . {for measuring evenness}	21/08	. . for measuring thickness
13/00	Measuring arrangements characterised by the use of fluids	21/085	. . . {using thermal means}
13/02	. for measuring length, width or thickness (G01B 13/08 takes precedence)	21/10	. for measuring diameters
13/03	. . by measuring coordinates of points	21/12	. . of objects while moving
13/04	. . specially adapted for measuring length or width of objects while moving	21/14	. . internal diameters {(of boreholes or wells E21B 47/08)}
13/06	. . for measuring thickness	21/16	. for measuring distance of clearance between spaced objects
13/065	. . . {Height gauges}	21/18	. for measuring depth
13/08	. for measuring diameters	21/20	. for measuring contours or curvatures, e.g. determining profile
13/10	. . internal diameters	21/22	. for measuring angles or tapers; for testing the alignment of axes
13/12	. for measuring distance or clearance between spaced objects or spaced apertures (G01B 13/18 takes precedence)	21/24	. . for testing alignment of axes
13/14	. for measuring depth	21/26	. . for testing wheel alignment
13/16	. for measuring contours or curvatures	21/28	. for measuring areas
13/18	. for measuring angles or tapers; for testing the alignment of axes	21/30	. for measuring roughness or irregularity of surfaces
13/19	. . for testing the alignment of axes	21/32	. for measuring the deformation in a solid
13/195	. . for testing wheel alignment	2210/00	Aspects not specifically covered by any group under G01B, e.g. of wheel alignment, caliper-like sensors
13/20	. for measuring areas, e.g. pneumatic planimeters	2210/10	. Wheel alignment
13/22	. for measuring roughness or irregularity of surfaces	2210/12	. . Method or fixture for calibrating the wheel aligner
13/24	. for measuring the deformation in a solid	2210/14	. . One or more cameras or other optical devices capable of acquiring a two-dimensional image
15/00	Measuring arrangements characterised by the use of electromagnetic waves or particle radiation, e.g. by the use of microwaves, X-rays, gamma rays or electrons (characterised by the use of optical techniques G01B 9/00, G01B 11/00)	2210/143	. . . One or more cameras on each side of a vehicle in the main embodiment
15/02	. for measuring thickness	2210/146	. . . Two or more cameras imaging the same area
15/025	. . {by measuring absorption}	2210/16	. . Active or passive device attached to the chassis of a vehicle
15/04	. for measuring contours or curvatures	2210/18	. . Specially developed for using with motorbikes or other two-wheeled vehicles
15/045	. . {by measuring absorption}	2210/20	. . Vehicle in a state of translatory motion
15/06	. for measuring the deformation in a solid	2210/22	. . Wheels in a state of motion supported on rollers, rotating platform or other structure substantially capable of only one degree of rotational freedom
15/08	. for measuring roughness or irregularity of surfaces	2210/24	. . Specially developed for using with trucks or other heavy-duty vehicles
17/00	Measuring arrangements characterised by the use of infrasonic, sonic or ultrasonic vibrations		
17/02	. for measuring thickness		
17/025	. . {for measuring thickness of coating}		
17/04	. for measuring the deformation in a solid, e.g. by vibrating string		
17/06	. for measuring contours or curvatures		
17/08	. for measuring roughness or irregularity of surfaces		

G01B

- 2210/26 . . Algorithms, instructions, databases, computerized methods and graphical user interfaces employed by a user in conjunction with the wheel aligner
- 2210/28 . . Beam projector and related sensors, camera, inclinometer or other active sensing or projecting device
- 2210/283 . . . Beam projectors and related sensors
- 2210/286 Projecting a light pattern on the wheel or vehicle body
- 2210/30 . . Reference markings, reflector, scale or other passive device
- 2210/303 . . . fixed to the ground or to the measuring station
- 2210/306 . . . Mirror, prism or other reflector
- 2210/40 . Caliper-like sensors
- 2210/42 . . with one or more detectors on a single side of the object to be measured and with a backing surface of support or reference on the other side
- 2210/44 . . with detectors on both sides of the object to be measured
- 2210/46 . . with one or more detectors on a single side of the object to be measured and with a transmitter on the other side
- 2210/48 . . for measurement of a wafer
- 2210/50 . Using chromatic effects to achieve wavelength-dependent depth resolution
- 2210/52 . Combining or merging partially overlapping images to an overall image
- 2210/54 . Revolving an optical measuring instrument around a body
- 2210/56 . Measuring geometric parameters of semiconductor structures, e.g. profile, critical dimensions or trench depth
- 2210/58 . Wireless transmission of information between a sensor or probe and a control or evaluation unit
- 2210/60 . Unique sensor identification
- 2210/62 . Support for workpiece air film or bearing with positive or negative pressure
- 2210/64 . Interconnection or interfacing through or under capping or via rear of substrate in microsensors
- 2210/66 . Rock or ground anchors having deformation measuring means
- 2290/00 Aspects of interferometers not specifically covered by any group under [G01B 9/02](#)**
- 2290/10 . Astronomic interferometers
- 2290/15 . Cat eye, i.e. reflection always parallel to incoming beam
- 2290/20 . Dispersive element for generating dispersion
- 2290/25 . Fabry-Perot in interferometer, e.g. etalon, cavity
- 2290/30 . Grating as beam-splitter
- 2290/35 . Mechanical variable delay line
- 2290/40 . Non-mechanical variable delay line
- 2290/45 . Multiple detectors for detecting interferometer signals
- 2290/50 . Pupil plane manipulation, e.g. filtering light of certain reflection angles
- 2290/55 . Quantum effects
- 2290/60 . Reference interferometer, i.e. additional interferometer not interacting with object
- 2290/65 . Spatial scanning object beam
- 2290/70 . Using polarization in the interferometer